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PATENT  
8031-1028

IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Yoshihiro NONAKA Conf. 5218

Application No. 10/648,256 Group 2811

Filed August 27, 2003 Examiner O. Nadav

SEMICONDUCTOR INTEGRATED CIRCUIT,  
METHOD OF MANUFACTURING SEMICONDUCTOR  
INTEGRATED CIRCUIT, CHARGE PUMP CIRCUIT,  
LAYOUT DESIGNING APPARATUS, AND LAYOUT  
DESIGNING PROGRAM

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying document, a copy of which is attached to this statement, is made of record on the enclosed Form PTO-1449.

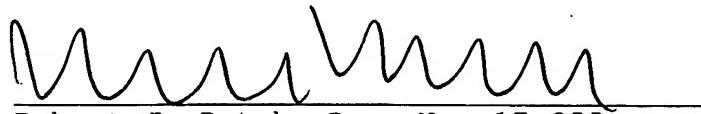
A concise explanation of the relevance of this item is that this reference was cited by the Chinese Patent Office in the corresponding Chinese Application Serial No. 03158127.7. A copy of the Chinese Official Action and English translation in which it was cited is attached hereto.

Under the provisions of 37 CFR 1.97(e), the undersigned hereby certifies that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign Patent Office in a

counterpart foreign application not more than three months prior to the filing of this Statement.

Respectfully submitted,

YOUNG & THOMPSON

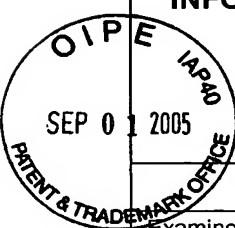


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RJP/lk

September 1, 2005



## **INFORMATION DISCLOSURE CITATION IN AN APPLICATION**

(Use several sheets if necessary)

Attorney Docket No.:  
**8031-1028**

**Application No.:**  
**10/648.256**

Applicant:  
**Yoshihiro NONAKA**

**Filing Date:**

Group Art Unit:  
**2811**

## **U.S. PATENT DOCUMENTS**

## **FOREIGN PATENT DOCUMENTS**

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**

**EXAMINER:**

DATE CONSIDERED

**EXAMINER:** Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

\* Abstract provided for the Examiner's convenience